Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/787,668	DEHAAN ET AL.
Examiner	Art Unit
Tam M. Nguyen	1764

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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
INTERFRENCE SEARCHED - SEE PGPUB PRINTOUT	10/30/2006	TN